

**Search Notes**

Application/Control No.

10/611,896

Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
257	52, 57	5/4/2005	TT
257	59-61	5/4/2005	TT
257	72	5/4/2005	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR